

## Electronic Supplementary Information

### **Hybrid of g-C<sub>3</sub>N<sub>4</sub> and porphyrin-based covalent organic frameworks via liquid-assisted grinding for enhanced visible-light-driven photoactivity**

Yuxia Hou,<sup>\*[a]</sup> Cheng-Xing Cui,<sup>[a]</sup> Enhui Zhang,<sup>[a]</sup> Ji-Chao Wang,<sup>\*[a]</sup> Ying Li,<sup>[a]</sup>  
Yuping Zhang,<sup>[a]</sup> Yuquan Zhang,<sup>[a]</sup> Qing Wang,<sup>[a]</sup> and Jianzhuang Jiang<sup>\*[b]</sup>

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[a] Y. Hou, C. Cui, E. Zhang, J. Wang, Y. Li, Y. Zhang, Y. Zhang, Q. Wang

Department of Chemistry and Chemical Engineering

Henan Institute of Science and Technology

Xinxiang, 453003 (China)

E-mail: yxhou@hist.edu.cn; wangjichao@hist.edu.cn

[b] Prof. J. Jiang

Beijing Key Laboratory for Science and Application of Functional Molecular and

Crystalline Materials

Department of Chemistry

University of Science and Technology Beijing

Beijing, 100083 (China)

Fax: (+86) 10-6233-2592

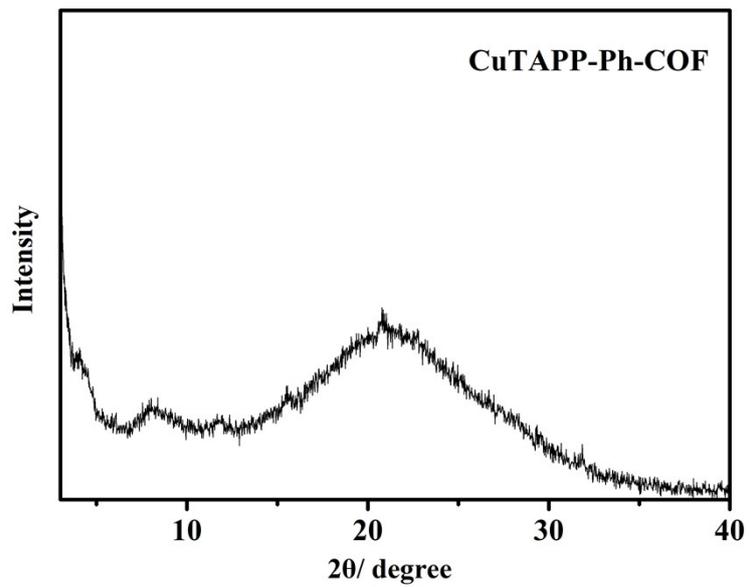
E-mail: jianzhuang@ustb.edu.cn

## **Physical measurements**

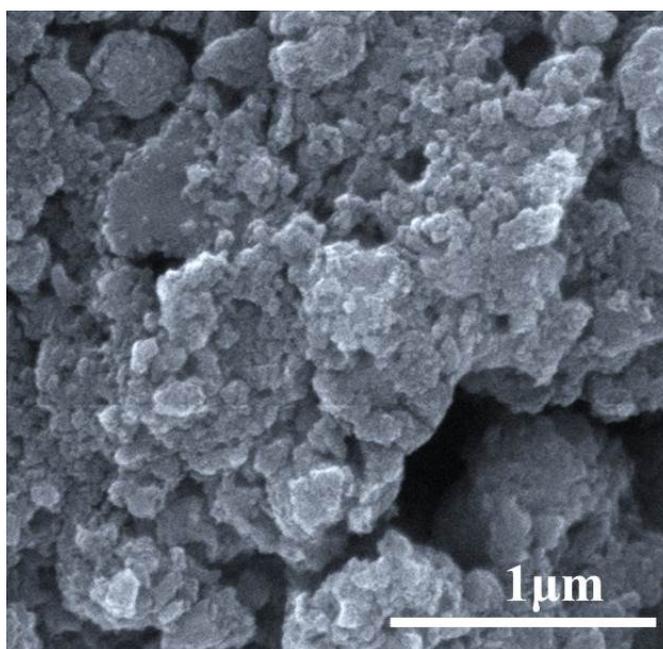
Fourier transform infrared (FT-IR) spectra were performed as KBr pellets using a Bruker Tensor 37 spectrometer with  $2\text{ cm}^{-1}$  resolution. Powder X-ray diffraction (PXRD) data were collected on a Bruker D8 Advance XRD diffractometer using Cu-K $\alpha$  radiation ( $\lambda = 1.54060\text{ \AA}$ ) at room temperature. Transmission electron microscopy (TEM) images were measured on a JEOL JEM-2100 electron microscope operated at 200 kV. Scanning electron microscopy (SEM) images were obtained using a JEOL JEM-6510A scanning electron microscopy. For TEM imaging, a drop of freshly prepared sample solution was cast onto a carbon copper grid. For SEM imaging, a drop of freshly prepared sample solution was cast onto a silicon slice, and then Au (1-2 nm) was sputtered onto the grids to prevent charging effects and to improve the image clarity. X-ray photoelectron spectroscopy (XPS) was carried out on PHI 5300 ESCA System (Perkin-Elmer, USA). The excitation source is Al K $\alpha$  radiation.

## **Photoelectrochemical characterization.**

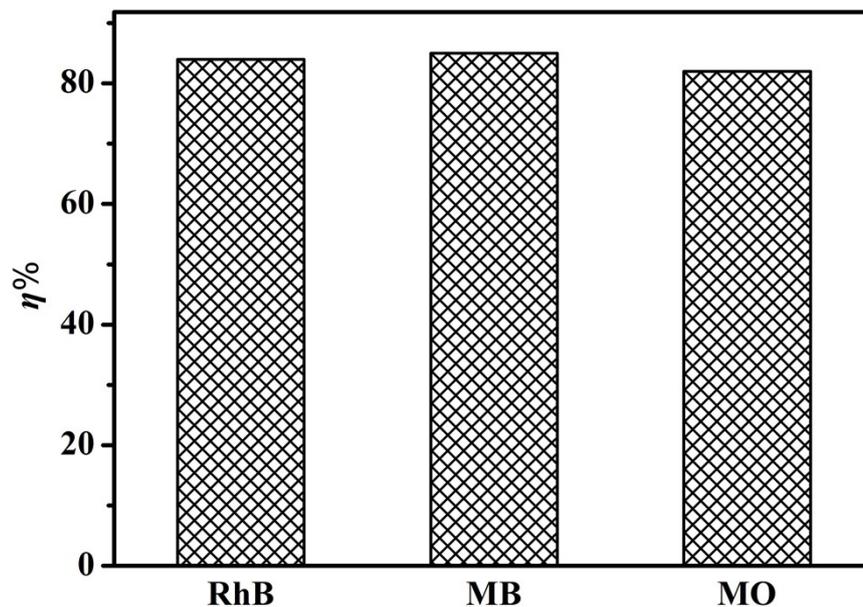
The photocurrent measurement were performed on three-electrode system using an electrochemical workstation. The cleaned ITO glass deposited with samples, Pt and Ag/AgCl electrode were used as working electrode, counter electrode, and reference electrode, respectively. The light source was a 300 W Xe lamp equipped with an ultraviolet cutoff filter ( $> 400\text{ nm}$ ) and  $0.05\text{ M Na}_2\text{SO}_4$  aqueous solution acted as the electrolyte.



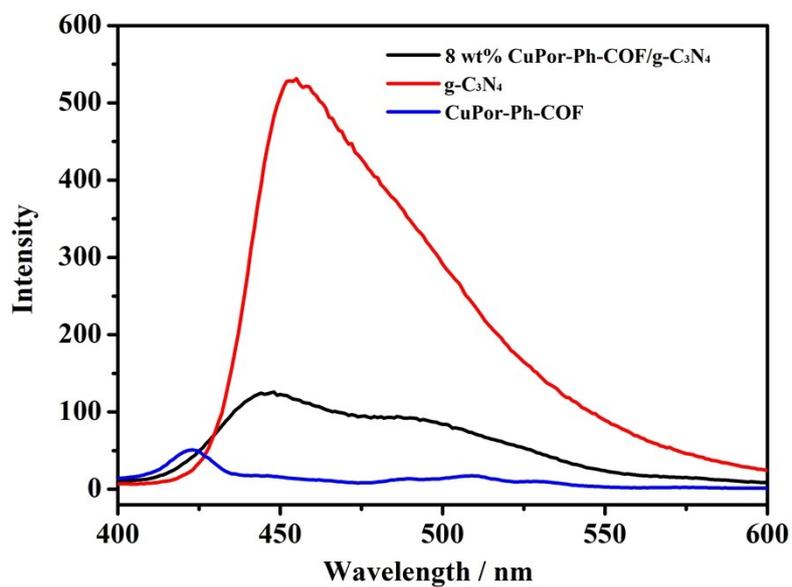
**Fig. S1** Experimental PXR D patterns of CuPor-Ph-COF prepared by LAG.



**Fig. S2** SEM images of CuPor-Ph-COF



**Fig. S3** Photocatalytic degradation of RhB, methylene blun (MB), and methyl orange (MO) in the presence of CuPor-Ph-COF/g-C<sub>3</sub>N<sub>4</sub> composites under visible-light irradiation.



**Fig. S4** Photoluminescence spectra of CuPor-Ph-COF/g-C<sub>3</sub>N<sub>4</sub>, CuPor-Ph-COF and g-C<sub>3</sub>N<sub>4</sub>.